FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. APPLN. NO. PATENT AND TRADEMARK OFFICE MIC-20 **APPLICANT INFORMATION DISCLOSURE** Pary Baluswamy et al. STATEMENT BY APPLICANT FILING DATE GROUP ARTP 1756 Herewith **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT **FILING DATE** DATE **CLASS SUBCLASS** NAME **INITIAL** NUMBER IF APPROPRIATE SRM 5,932,491 8/1999 Wald et al. 438 734 SPM 6,120,952 9/2000 Pierrat et al. 430 30 257 797 SPM 6,144,109 11/2000 Stanton et al. 5 6,214,497 4/2001 Stanton 430 SPM Sem 5/2001 Futrell et al. 5 6,238,824 430 SPM 6,242,816 6/2001 Stanton et al. 257 797 Sem 6,245,468 7/2001 Futrell et al. 5 430 Sem 5 6.258.489 7/2001 Stanton et al. 430 5em 6,284,419 9/2001 Pierrat et al. 430 30 SPW 11/2001 430 30 6,319,644 Pierrat et al. SPW 2001/0002304A1 5/2001 Pierrat et al. 430 30 SRIM 2001/0023043A1 9/2001 Futrell et al. 430 5 2001/0023045A1 9/2001 SRM Pierrat et al. 430 30 Sem 2001/0033979A1 5 10/2001 **Baggenstoss** 430 **FOREIGN PATENT DOCUMENTS TRANSLATION EXAMINER DOCUMENT NUMBER** DATE COUNTRY CLASS SUBCLASS INITIAL **YES** NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) **EXAMINER** INITIAL Peterson, J.S., "Analytical Description of Anti-scattering and Scattering Bar Assist Features," Sem Proceedings of SPIE: Optical Microlithography XIII, vol. 4000, pp. 77-89 (March 1-3, 2000)

EXAMINER Mohamedulla

DATE CONSIDERED 3/3/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.